

Title (en)

Contact pin for testing circuit boards.

Title (de)

Kontaktstift für die Funktionsprüfung von Leiterplatten.

Title (fr)

Broche de contact pour tester la fonction des circuits imprimés.

Publication

**EP 0341454 B1 19931215 (DE)**

Application

**EP 89106910 A 19890418**

Priority

DE 8806162 U 19880509

Abstract (en)

[origin: EP0341454A2] The invention relates to a contact pin (2) for the functional testing of printed-circuit boards or the like, having a contact head (6) which is constructed on one free end and comes to a point in a converging manner. The contact head (6) is provided with a polished plane (14) running through the tip (12) of the contact head, parallel to the axis (10) of the contact pin. The cutting edges produced in this way improve the contact when a soldering pad or a through-plated hole is covered or contaminated with an oxide layer. In the base region (16) of the contact head (6) which is brought to a point in a converging manner, there is additionally constructed a groove (18) which runs over the complete circumference of the base, is open towards the contact tip (12) and is used to trap the component legs when making contact with them. <IMAGE>

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